

P-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}$ (m Ω)(Typ.)	I _D (A) ^a	Q _g (Typ.)			
- 40	7.6 at V _{GS} = - 10 V	- 95	65 nC			
- 40	10 at V _{GS} = - 4.5 V	- 80	65 110			

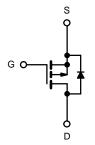
FEATURES

- DT-Trench Power MOSFET
- 100 % R_g and UIS Tested



APPLICATIONS

- PWMApplications
- LoadSwitch
- PowerManagement



P-Channel MOSFET

TO-220AB					
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Top View

Parameter		Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	- 40	V	
Gate-Source Voltage		V_{GS}	± 20	v
Continuous Drain Current (T _J = 150 °C)	$T_{C} = 25 ^{\circ}\text{C}$ $T_{C} = 70 ^{\circ}\text{C}$ $T_{A} = 25 ^{\circ}\text{C}$ $T_{A} = 70 ^{\circ}\text{C}$	I _D	- 95 ^a - 70 ^a - 30 ^{b, c} - 18 ^{b, c}	A
Pulsed Drain Current		I _{DM}	- 380	_ ^
Continuous Source-Drain Diode Current	$T_C = 25 ^{\circ}C$ $T_A = 25 ^{\circ}C$	I _S	- 95 ^a - 72 ^{b, c}	
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	- 93	
Single Pulse Avalanche Energy	L = 0.1 11111	E _{AS}	78	mJ
Maximum Power Dissipation	$T_{C} = 25 ^{\circ}\text{C}$ $T_{C} = 70 ^{\circ}\text{C}$ $T_{A} = 25 ^{\circ}\text{C}$ $T_{A} = 70 ^{\circ}\text{C}$	P _D	126 80.5 7.15 ^{b, c} 4.58 ^{b, c}	w
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C
Soldering Recommendations (Peak Temperature		260		

THERMAL RESISTANCE RATINGS						
Parameter	Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	25	45	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	1.0	1.6	C/VV	

Notes:

- a. Package limited.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under Steady State conditions is 54 °C/W.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 40			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	_{DS} /T _J I _D = - 250 μA		- 30		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	10 = - 230 μΑ		6.3		I IIIV/ C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1.0		- 3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zone Oote Valte on Decis Ourseld		V _{DS} = - 40 V, V _{GS} = 0 V			- 1		
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = - 40 V, V _{GS} = 0 V, T _J = 55 °C	1		- 10	μA	
On-State Drain Current ^a	I _{D(on)}	V _{DS} = - 5 V, V _{GS} = - 10 V	- 95			Α	
	D	V _{GS} = - 10 V, I _D = - 30 A		7.1	.1 9.8		
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 25 A		10	13	mΩ	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 30		62		S	
Dynamic ^b	•						
Input Capacitance	C _{iss}			7590		pF	
Output Capacitance	C _{oss}	$V_{DS} = -20$, $V_{GS} = 0$ V, $f = 1$ MHz		698			
Reverse Transfer Capacitance	C _{rss}			350			
Total Gate Charge	Qg			65			
Gate-Source Charge	Q _{gs}	$V_{DS} = -20$, $V_{GS} = -10$ V, $I_{D} = -30$ A		19		nC	
Gate-Drain Charge	Q _{gd}			27			
Gate Resistance	R_g	f = 1 MHz		3.9		Ω	
Turn-On Delay Time	t _{d(on)}			20			
Rise Time	t _r	$V_{DD} = -20 \text{ V}, R_1 = 15 \Omega$		65			
Turn-Off Delay Time	t _{d(off)}	$I_D \cong -30 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 3\Omega$		100		ns	
Fall Time	t _f	, and the second		93			
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			- 95	۸	
Pulse Diode Forward Current ^a	I _{SM}				- 380	A	
Body Diode Voltage	V _{SD}	I _S = - 30 A		- 0.8	- 1.5	V	
Body Diode Reverse Recovery Time	t _{rr}			27		ns	
Body Diode Reverse Recovery Charge	Q _{rr}	1 20 A dl/dt 400 A/:- T 05 00		20		nC	
Reverse Recovery Fall Time	t _a	$I_F = -30 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$		18			
Reverse Recovery Rise Time	t _b			19		ns	

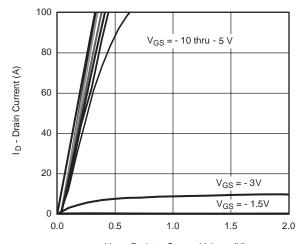
Notes:

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$

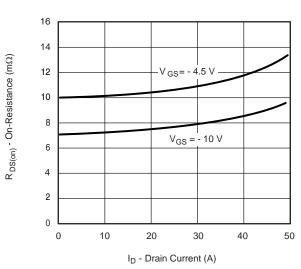
b. Guaranteed by design, not subject to production testing.



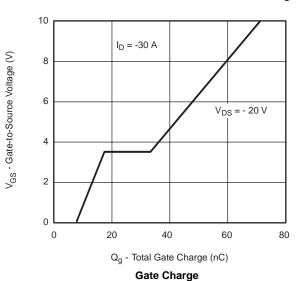


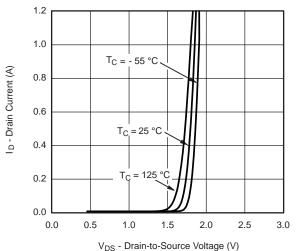
V_{DS} - Drain-to-Source Voltage (V)

Output Characteristics

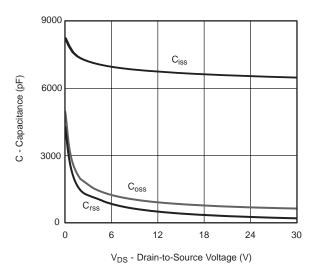


On-Resistance vs. Drain Current and Gate Voltage

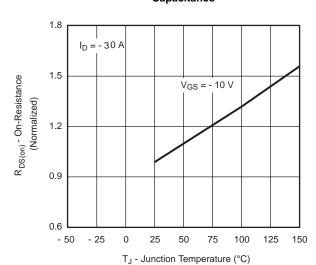




Transfer Characteristics

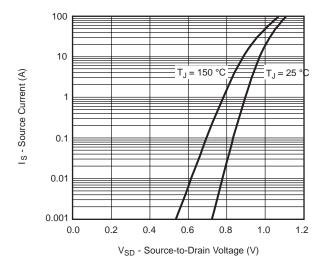


Capacitance

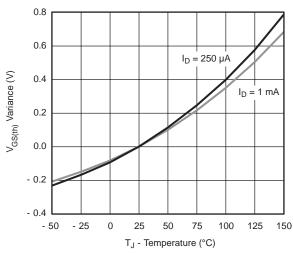


On-Resistance vs. Junction Temperature

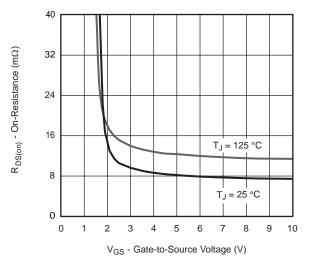




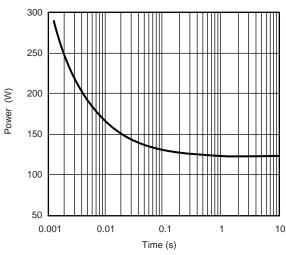
Source-Drain Diode Forward Voltage



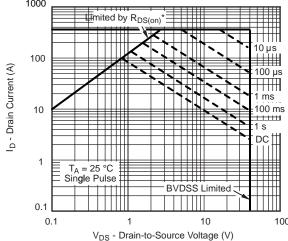
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage



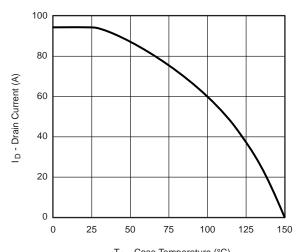
Single Pulse Power, Junction-to-Ambient



* V_{GS} > minimum V_{GS} at which R_{DS(on)} is specified

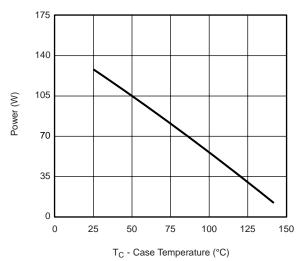
Safe Operating Area, Junction-to-Ambient

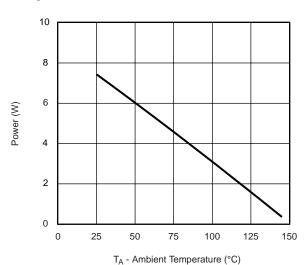




 $T_{\mbox{\scriptsize C}}$ - Case Temperature (°C)

Current Derating*

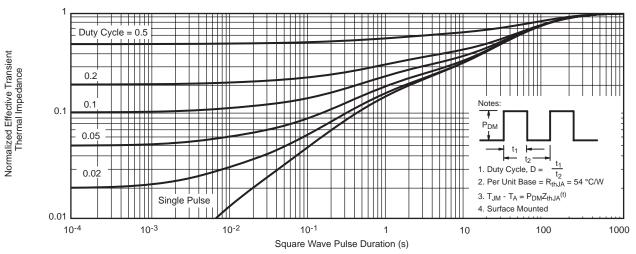




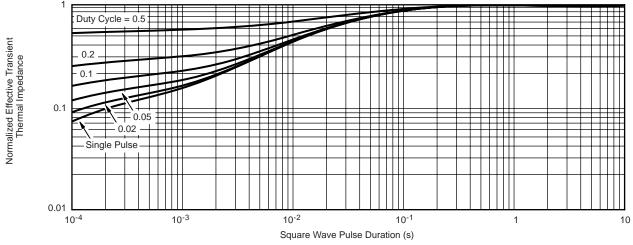
Power, Junction-to-Case Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient

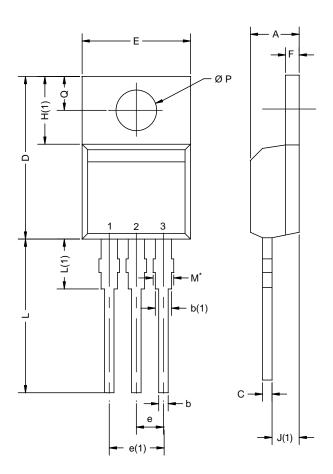


Normalized Thermal Transient Impedance, Junction-to-Case





TO-220AB



	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
Α	4.25	4.65	0.167	0.183
b	0.69	1.01	0.027	0.040
b(1)	1.20	1.73	0.047	0.068
С	0.36	0.61	0.014	0.024
D	14.85	15.49	0.585	0.610
Е	10.04	10.51	0.395	0.414
е	2.41	2.67	0.095	0.105
e(1)	4.88	5.28	0.192	0.208
F	1.14	1.40	0.045	0.055
H(1)	6.09	6.48	0.240	0.255
J(1)	2.41	2.92	0.095	0.115
L	13.35	14.02	0.526	0.552
L(1)	3.32	3.82	0.131	0.150
ØΡ	3.54	3.94	0.139	0.155
Q	2.60	3.00	0.102	0.118

 $^{^{\}star}$ M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM

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